



KLA RS200+

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Manufacturer	KLA
Main functions	The sheet resistance of a conductive thin film is tested, and the thickness is calculated based on the relationship between resistance and film thickness.
Capable of supporting wafer size	8-inch (Open Cassette)
Procurement time	2022
Random accessories	F Probe , a set of resistor blocks (27.9kΩ/sq.) 279.4Ω/sq, 2.794Ω/ sq
Hardware configuration	<ul style="list-style-type: none">• Galil Motion Controller• I7 Computer• Dual Probe Arm: P1 / P2• LP1: 200mm OCA+• LP2: 200mm OCA+
Software version	RS SW: 10.0.0.6

SPECIFICATIONS

- Measurement range: $> 5 \text{ m}\Omega/\text{sq.}$ to $< 5 \text{ M}\Omega/\text{sq}$
- Measurement repeatability, based on KLA-Tencor's "Probe Qualification Test" @ 1" test diameter, using the appropriate probe head: $< 0.2\%$ (1σ)
- Reproducibility: Representative metals (e.g. Cu, W, TiN) $< 0.5\%$ (1σ)
- Edge exclusion: From the conductive film edge for the following the probe heads:
 - 25 mil pitch -1 mm with "enhanced" probe position
 - 25 mil pitch -3 mm with "standard" probe position
 - 40 mil pitch -4 mm with "standard" probe position
 - 62.5 mil pitch -5 mm with "standard" probe position
- Temperature measurement accuracy: $\pm 0.5^\circ\text{C}$
- Temperature measurement repeatability: $\pm 0.2^\circ\text{C}$
- Throughput: based on 5-site test with wafer alignment, fixed current and temperature compensation.
 - 200 mm Single SMIF: $\geq 110 \text{ WPH}$
- Measurement Capabilities
 - Routine check: 1-30 sites programmable (ASTM standard tests included)
 - XY maps and flexible, user-defined patterns: up to 1,200 sites programmable
- Analysis Capabilities
 - Contour/3-D map: 49, 81, 121, 225, 361, 441, 625 sites
 - Diameter scan: 49, 81, 121, 225, 361, 441, 625 sites
 - Probe qualification test: 20 sites
 - Trend charts
 - Recipe editing and data extraction capability
 - Average, difference and ratio maps
 - Temperature coefficient of resistance correction